

Notice of References Cited	Application/Control No. 10/736,386		Applicant(s)/Patent Under Reexamination WHITEFIELD ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Abugov et al.; A Yield Based Replacement for Capability Indexes; 1995 IEEE/SEMI Advanced Semiconductor Manufacturing Conference; pp. 209-212.
	V	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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